## Coated conductors containing grains with big aspect ratios

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## A bstract

It is shown that the critical currents of high- $T_c$  superconducting tapes fabricated by the coated conductor technologies are enhanced considerably if grain arrangements with large elective grain boundary areas are used. Increasing the aspect ratios of the grains reduces the deleterious elects of the grain boundaries. A practical road to competitive high- $T_c$  cables is proposed.

C ables that are superconducting at 77K require the use of polycrystalline high- $T_c$ -superconductors [1] with large critical currents. Form aterials with su cient pinning, such as YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7</sub> [2], three strategies have been found to achieve this goal. The rst is to enhance the critical current density of the grain boundaries. This can be done by aligning the grains along all three m a jor axes to within few degrees [3]. This approach is based on the fact that the grain boundary critical current density is an exponential function of the m isorientation angle [4], dropping by three to four orders of m agnitude as the m isorientation angle is increased from 0 to 45. Second, for a given m isorientation angle, the grain boundary critical current density is enhanced by appropriate doping [5, 6]. The third strategy consists in maxim izing the elective grain boundary area by optimizing the arrangement and the shape of the grains, as illustrated in Fig. 1. In the simplest case, this can be achieved by utilizing grains with large aspect ratios [7, 8].

Them ost prom ising candidates for econom ically competitive cables are tapes fabricated by coated conductor technologies, such as ion beam -assisted deposition (IBAD) [9], rolling-assisted biaxially-textured substrates (RAB iT S) [10, 11], and inclined-substrate deposition (ISD) [12, 13]. For practical applications, the coated conductor technologies are superior to the competing powder in tube technology which is based on B i-based high-T<sub>c</sub> superconductors are decisively sm aller and the ReB  $a_2$ C  $u_3$ O  $_7$  superconductors, where Re is Y or a rare earth, o er the potential of operation at 77 K in large magnetic elds. The best coated

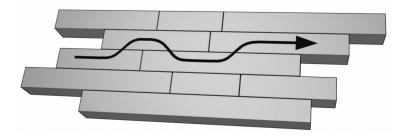


Figure 1: Sketch of a brick-wall like arrangement of grains in a coated conductor. The arrow illustrates a possible path for the supercurrent. The current traverses grain boundaries with large areas.

conductors fabricated at present support critical current densities exceeding  $10^6 A = cm^2$  over m eter lengths. Taking the substrate thickness and thereby the whole cross-section of the tape into account, these current densities correspond to engineering critical current densities of several  $10^4 A = cm^2$ . These values are achieved by aligning the grains along all axes with a spread of m isorientation angles sm aller than 10 . Because the corresponding grain alignment processes are slow and costly, strategies are urgently sought to enhance the critical current density of such tapes for a given m isorientation spread. The solution of this problem would provide the key to commercially viable large scale applications of high-T<sub>c</sub> superconductors.

A pplying the concepts conceived in R ef. [7] to coated conductors, we suggest to enhance their critical currents  $I_c$  by using grains with large aspect ratios to optim ize the elective grain boundary area (see Fig. 1). A coording to the model calculations described below, an increase of the average grain aspect ratio causes a monotonous, strong increase of  $I_c$ , as well as a reduction of the sensitivity of  $I_c$  to the average grain boundary angle.

The calculations perform ed to analyze the critical current of a given grain boundary network were based on a modi ed version of the algorithm developed by Holzapfel et al., as described in detail in Ref. [14]. This algorithm has been designed to analyze the critical currents of grain boundary networks in coated conductors. The procedure considers two-dimensional grain networks characterized by a given spread of grain orientations. In such a network the algorithm searches for the cross-section that lim its the critical current, and then calculates the critical current of this cross-section. Because for the grain m isorientations of interest the grain boundaries do not act as Josephson junctions, and all phase e ects are negligible. As shown in Ref. [14], the results of such calculations agree well with transport measurements of  $I_c$ . For our work, the algorithm was optim ized for speed, so that several thousand networks, each containing  $10^5 \ 10^6$  grains, could be calculated on a personal computer. This optim ization was achieved by accelerating the search for the lim iting cross-section, storing inform ation gained in the individual search routines.

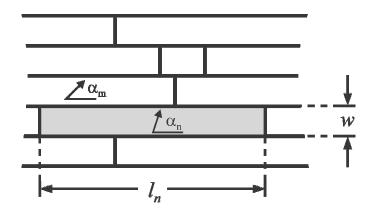


Figure 2: Illustration of the grain arrangem ent considered in the calculations.

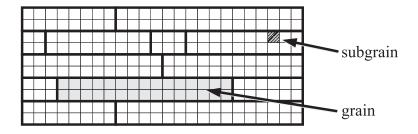


Figure 3: Sketch of the grain and subgrain arrangement in a small array consisting of  $24 \times 10$  subgrains. The thick lines represent the grain boundaries. The thin lines show the boundaries between the subgrains.

To analyze the e ect of the enhancement of the elective grain boundary area on  $I_c$ , two-dimensional arrays of N grains arranged in brickwall-type structures were considered (see Fig. 2 and Fig. 3). In these structures to each grain an in-plane orientation  $_i$  was assigned (see Fig. 2). W hereas the same width w was selected for all grains, the length  $l_i$  of each grain was random ly chosen, following a G aussian distribution with a full width at half maximum (FW HM) of l=5 centered around the average length l, clipped to zero below w=2 and above 250 w. The average aspect ratio of the grains is then given by N<sup>-1</sup>  $l_i$ =w. As the critical current of the network is also a ected by the intragranular critical current density  $J_c^{\rm grain}$ , each grain was split into two rows of square subgrains (see Fig. 3) and the critical current density of the boundaries between the subgrains was set to equal  $J_c^{\rm grain}$ .

The angles  $_{i}$  were also random ly chosen, again following a G aussian distribution, this time centered at 0 with a FW HM -spread . M isorientation angles  $_{i}$  exceeding 45 were clipped.

The grain arrangements and the G aussian distributions were selected to provide clear and simple rules for the design of the model systems. These systems are presented as rst examples for practical conductors with more complicated designs. A swill be obvious, the conclusions of our work are not a ected by the particular choice of the model systems used for the calculations.

In case self eld e ects are negligible, the critical current of the grain boundary between two grains, n and m, is well approximated by the product of the boundary area and its critical current density  $J_c^{n\,m}$ . To calculate the critical current density, an exponential dependence on the m isorientation angle j<sub>n</sub> m j was used [4]

$$J_{c}^{n,m} = J_{c}^{\text{grain}} \exp\left(\frac{j_{n} m j}{m}\right):$$
(1)

Here  $J_c^{\rm grain}$  was set to 5 10A = cm<sup>2</sup> and to 5.3, values typical for coated conductors operated at 77K.W ith this, the in uence of the grain aspect ratio on the critical current of the network was analyzed. For a series of average aspect ratios and grain orientation distributions the critical current densities of networks 200 subgrains wide and 1,000 subgrains long were calculated. Depending on the grains average aspect ratio these networks consisted of about 500 to 50,000 grains. For each set of parameters the critical current densities of at least 20 di erent networks have been determ ined and the resulting critical current densities. The error bars display the standard deviation of the calculated currents as determ ined from the averaging process.

As shown by the gure, the critical current density of the network rises strongly and monotonously with increasing aspect ratio of the grains. The gradient is largest at small aspect ratios, which is attributed to the relatively small current densities of these networks, which are barely a ected by  $J_c^{\rm grain}$ . For small m isorientation angles and large aspect ratios the current densities saturate at  $J_c^{\rm grain}$ . The calculated  $J_c$  enhancements are in pressive. For example,

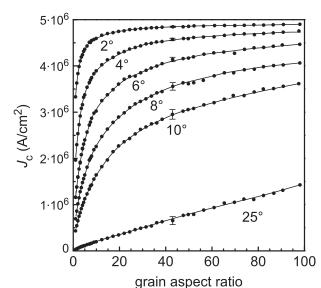


Figure 4: P lot of the critical current density  $J_c$  as a function of the average grain aspect ratio, calculated for various grain alignment spreads . The data have been obtained in calculations on grain networks consisting of  $1000 \times 200$  subgrains. Each datapoint relects an average of at least 20 calculations. The lines are guides to the eye.

for grain m isorientations resulting from an alignment spread of 10, the current densities are enhanced from 4:4 1 $bA = cm^2$  to 1:6 1 $bA = cm^2$  if the average aspect ratio is increased from 1 to 10.

Further, the dependence of the critical current on the spread of the grain orientations was analyzed, considering various average aspect ratios. The results of these calculations are shown in Fig. 5. As expected, for sm allangular spreads the critical current densities of the networks equal the intragrain critical current density, independent of the aspect ratios. Surprisingly, in networks consisting of grains with large aspect ratios, the well known exponential drop of  $J_c$  with m isorientation is modiled and dam ped. A pproaching the intragranular current density, coated conductors with a grain alignment as large as 10 and grain aspect ratios of 50 have the same critical current density as standard coated conductors (aspect ratio 1) with a misalignment of only 2. Networks with aspect ratios 100 support critical current densities exceeding  $10^6 \text{A} = \text{cm}^2$  for grain alignment spreads as large as = 25.

A lthough the presented calculations consider particularly simple, m athem atically accessible tape structures and neglect self eld and second order e ects, they clearly show the usefulness of optim izing the grain structure in the coated conductor technologies, in particular the use of grains with large aspect ratios.

The realization of coated conductors with big aspect ratios we consider to be technologically straightforward. The IBAD or ISD processes may be modied so that grains with large aspect ratios are nucleated, for example, by taking

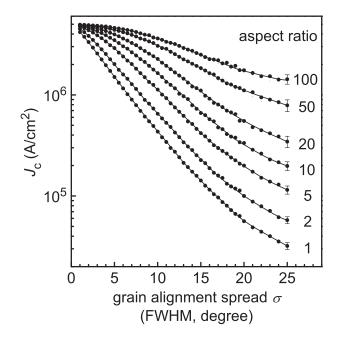


Figure 5: P lot of the critical current density  $\rm J_c$  as a function of the grain alignment spread , calculated for various average grain aspect ratios. The data have been obtained in calculations on grain networks consisting of 1000 \* 200 subgrains. Each datapoint rejects an average of at least 20 calculations. The lines are guides to the eye.

advantage of anisotropic di usion during grain nucleation and growth. The RABITS architecture is particularly suited for the implementation of grains with big aspect ratios. For example, metallic tapes with standard RABITS texture, consisting of N i-alloys or steel, may be rolled and annealed in mass production processes to contain long grains which are aligned parallel to the length of the tape. Standard RABITS bu er layer and superconductor epitaxy, performed by cheap deposition processes under development, will reproduce this grain structure in the ReBa<sub>2</sub>Cu<sub>3</sub>O<sub>7</sub> -based superconductor, yielding at competitive costs high-T<sub>c</sub> tapes with very large critical currents.

In summary, suggesting a solution to the grain boundary problem, we propose a practical road to competitive high- $T_c$  cables: fabricating doped coated conductors containing grains with big aspect ratios.

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